

Search Notes

Application/Control No.

10/716,257

Examiner

John Q. Nguyen

Applicant(s)/Patent under
Reexamination

AARON ET AL.

Art Unit

3654

SEARCHED

Class	Subclass	Date	Examiner
242	332.4 332.7 532.1 532.5 582	12/1/2005	JN
242	586.4	12/1/2005	JN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR